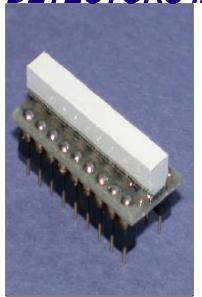
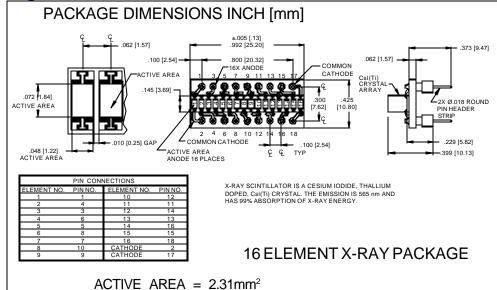
PHOTONIC X-RAY, Silicon Photodiode Array, Photoconductive **DETECTORS** INC. (with Csl(Ti) scintillation crystals)Type PDB-C216-C





FEATURES

- .062 inch centers
- Stackable
- CsI(Ti) crystals
- Low capacitance

DESCRIPTION

The **PDB-C216-C** is a common cathode, monolithic silicon PIN photodiode 16 element array. Designed to be stacked end to end to form a line of pixels. Supplied with X-Ray CsI(Ti) scintillation crystals.

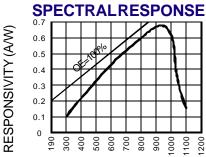
APPLICATIONS

- Luggage X-ray
- X-Ray scanner
- X-Ray inspection

ABSOLUTE MAXIMUM RATING (TA=25°C unless otherwise noted)

SYMBOL	PARAMETER	MIN	MAX	UNITS
$V_{\mathtt{BR}}$	Reverse Voltage		50	V
T _{STG}	Storage Temperature	-40	+100	∘C
T _o	Operating Temperature Range	-20	+75	∘C
T _s	Soldering Temperature*		+265	∘C
IL	Light Current		500	mA

^{*1/16} inch from case for 3 secs max



WAVELENGTH(nm)

ELECTRO-OPTICAL CHARACTERISTICS (TA=25°C unless otherwise noted, without scintillator)

SYMBOL	CHARACTERISTIC	TEST CONDITIONS	MIN	TYP	MAX	UNITS
l _{sc}	Short Circuit Current	H = 100 fc, 2850 K	18	28		μΑ
I _D	Dark Current	$H = 0, V_R = 5 V$		5	50	nA
R _{SH}	Shunt Resistance	$H = 0, V_R = 10 \text{ mV}$	100	200		MΩ
TCR _{SH}	RSH Temp. Coefficient	$H = 0, V_R = 10 \text{ mV}$		-8		%/℃
C _J	Junction Capacitance	$H = 0, V_R = 0 V^{**}$		40	60	pF
λrange	Spectral Application Range	Spot Scan	350		1100	nm
λр	Spectral Response - Peak	Spot Scan		950		nm
V _{BR}	Breakdown Voltage	I = 10 μA	15	30		V
NEP	Noise Equivalent Power	V _R = 10 V @ Peak		2x10 ⁻¹⁴		W/ √ Hz
tr	Response Time	$RL = 50 \Omega V_R = 10 V$		15		nS

Information in this technical data sheet is believed to be correct and reliable. However, no responsibility is assumed for possible inaccuracies or omission. Specifications are subject to change without notice. ** f = 1 MHz [FORMNO.100-PDB-C216-CREVD]